


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 1077-3735		SERIAL NO. 19917.115	
LIST OF ART CITED BY APPLICANT (Use correct check if not empty)				APPLICANT Purando Concepts et al.			
				FILING DATE 07/1/04		GROUP 2815	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
2	AA	4,503,101	02/90	Young et al.			
2	AB	6,544,210 B2	05/03	Ajzura et al.			
2	AC	5,650,343	07/97	Leung et al.			
2	AD	4,104,491	10/91	Koh			
2	AE	2001/0043604 A1	11/01	Oda et al.			
2	AF	2001/0092973 A1	07/01	Leokandrag et al.			
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AL						
	AM						
	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
2	AR			Lee et al., "Investigation of poly-Si1-xGe1-x for dual-gate CMOS Technology," IEEE Electron Device Letters, Vol. 19, No. 7, 1998, pp. 247-249.			
2	AS			Wolf et al., "Silicon Processing for the VLSI Era Vol. 1 - Process Technology," Lifetime Press, 1986, pp. 191-194.			
	AT						
EXAMINER				DATE CONSIDERED 3/20/05			
*EXAMINER: Initial of reference considered, whether or not citation is in conformance with MPEP 609; Draw for enough citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2535		priority SERIAL NO. 101817175	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				priority FILING DATE 11/21/01		priority GROUP 2815	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
P	AA	5,759,908	06/93	Stock			
P	AB	2002/0019105 A1	02/02	Hattori et al.			
P	AC	2003/0162586 A1	04/03	Wallace et al.			
P	AD	2002/0182423 A1	12/02	Chu et al.			
P	AE	2002/0016557 A1	07/02	Matsuura et al.			
	AF						
	AG						
	AH						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AI						
	AJ						
OTHER REFERENCES (including Author, Title, Date, Periodic Pages, Etc.)							
	AK						
	AL						
	AM						
	AN						
EXAMINER 				DATE CONSIDERED 3/20/05			
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2536		priority SERIAL NO. 09/929,911 1617175	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micro Technology, Inc.			
				priority FILING DATE 11/21/01		priority GROUP 2815	
U.S. PATENT DOCUMENTS							
* Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
2	AA	6,462,381 B1	10/02	Beche et al.			
2	AB	5,999,675	12/99	Sogiyama			
2	AC	6,535,891 B1	04/03	Foretwa et al.			
2	AD	5,891,769	04/99	Ulaw et al.			
2	AE	6,653,714 B2	11/03	Mazzoni et al.			
2	AF	6,544,854 B1	04/03	Puchner et al.			
2	AG	6,620,671 B1	09/03	Wang et al.			
2	AH	6,358,806 B1	03/02	Puchner			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
2	AI	JP 11-177122 A	07/99	Sogiyama			
2	AJ	JP 1070746 A	10/98	Sogiyama			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AK		/				
	AL						
	AM						
	AN						
	AO						
EXAMINER			DATE CONSIDERED				
[Signature]			3/20/05				
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